Abstracts

Microwave on-wafer characterization of three-port devices using shield-based test-fixtures

T.E. Kulding, M.B. Jenner and S. Laursen. "Microwave on-wafer characterization of three-port devices using shield-based test-fixtures." 2001 MTT-S International Microwave Symposium Digest 01.3 (2001 Vol. III [MWSYM]): 1535-1538 vol.3.

The capability of shield-based test-fixture design used in conjunction with three-port device measurements is demonstrated. The reduction of forward coupling and common-ground parasitics facilitates simple de-embedding that can easily be applied to multi-port measurements. The procedure is detailed and the capability of the method is demonstrated with gigahertz device measurements.

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